WHAT IS CLAIMED IS:

1. An electronic component testing equipment (20) defined with a first horizontal axis, a second horizontal axis and a vertical axis, which are perpendicular to each other, the electronic component testing equipment (20) comprising:

a testing unit (30) comprising a testing chamber (31) and a chuck (32) disposed in the testing chamber for supporting a device under test (80);

a buffering unit (40) comprising a buffering chamber (41), and a pick and place member (42), a horizontal displacement device (43), a buffering device (44) and a vertical displacement device (45), which are disposed in the buffering chamber (44), the buffering chamber (44) having a first access (413) selectively communicating with an external environment, and a second access (414) selectively or directly communicating with the testing chamber (31), the pick and place member (42) being disposed on the horizontal displacement device (43) and drivenable by the horizontal displacement device to move into the testing chamber (31) through the second access (414) along the first horizontal axis, the buffering device (44) comprising a first tray (441) and a second tray (442) each for carrying one said device under test (80), the buffering device (44) being disposed on the vertical displacement device and drivenable by the vertical displacement device to move between a first position (P1) and a second position (P2) along the vertical axis, when the buffering device (44) is located at the first position (P1), the first tray (441) corresponding in position to the chuck (32) along the first horizontal axis for enabling the pick and place member (42) to transfer the device under test (80) disposed on the first tray (441) to the chuck (32) along the first horizontal axis, when the buffering device (44) is located at the second position (P2), the second tray (442) corresponding in position to the chuck (32) along the first horizontal axis for enabling the pick and place member (42) to transfer the device under test (80) disposed on the chuck (32) to the second tray (442) along the first horizontal axis; and

a dry air supplying device (70) communicating with the testing chamber (31) and the

buffering chamber (41) for supplying dry air into the testing chamber (31) and the buffering chamber (41);

wherein a dry air flow (F2) is supplied by the dry air supplying device (70) into the buffering chamber (41) and arranged adjacent to the first access (413);

wherein another dry air flow (F1) is supplied by the dry air supplying device (70) into the testing chamber (31) and arranged adjacent to the second access (414).

2. The electronic component testing equipment as claimed in claim 1, wherein a height of the first access of the buffering chamber along the vertical axis is smaller than or equal to one third of a height of the buffering chamber along the vertical axis.

3. The electronic component testing equipment as claimed in claim 1, further comprising a device under test storage seat; the buffering chamber is disposed on a top surface of the device under test storage seat.

4. The electronic component testing equipment as claimed in claim 1, wherein the first tray is provided with a pre-cooling mechanism; the second tray is provided with a heating mechanism.

5. The electronic component testing equipment as claimed in claim 1, further comprising a pick and place device disposed in the external environment for passing through the first access to place the device under test on the first tray and take out the device under test located on the second tray to the external environment.

6. The electronic component testing equipment as claimed in claim 1, wherein the buffering device comprises a frame disposed on the vertical displacement device; the first tray

comprises two first plates fixed to the frame and separated from each other along the second horizontal axis, and a passage formed between the two first plates and extending along the first horizontal axis; the second tray comprises two second plates fixed to the frame and separated from each other along the second horizontal axis, and a passage formed between the two second plates and extending along the first horizontal axis; when the buffering device is located at the first position, the pick and place member corresponds in position to the passage of the first tray along the first horizontal axis; when the buffering device is located at the second position, the pick and place member corresponds in position to the passage of the second tray along the first horizontal axis.

7. The electronic component testing equipment as claimed in claim 6, wherein the buffering unit comprises a base disposed in the buffering chamber; the vertical displacement device is disposed on a vertical surface of the base; the horizontal displacement device is disposed on a top of the base and extends from the top in a direction that the vertical surface faces toward.

8. The electronic component testing equipment as claimed in claim 7, wherein the horizontal displacement device comprises at least one linear displacement assembly disposed on the top of the base, and an extending arm disposed on said at least one linear displacement assembly and drivenable by said at least one linear displacement assembly to move along the first horizontal axis; the pick and place member is disposed on the extending arm.

9. The electronic component testing equipment as claimed in claim 8, wherein said at least one linear displacement assembly comprises a first linear displacement assembly disposed on the top of the base, and a second linear displacement assembly disposed on the first linear displacement assembly and drivenable by the first linear displacement assembly to

move along the first horizontal axis; the extending arm is disposed on the second linear displacement assembly and drivenable by the second linear displacement assembly to move along the first horizontal axis.

10. The electronic component testing equipment as claimed in claim 8, wherein the horizontal displacement device further comprises another linear displacement assembly disposed on the extending arm; the pick and place member is disposed on said another linear displacement assembly and drivenable by said another linear displacement assembly to move along the first horizontal axis.

11. The electronic component testing equipment as claimed in claim 1, wherein the electronic component testing equipment further comprises a baffle movably disposed on the buffering chamber to open or close the first access.

12. The electronic component testing equipment as claimed in claim 1, wherein the electronic component testing equipment further comprises a baffle movably disposed on the buffering chamber to open or close the second access.

13. The electronic component testing equipment as claimed in claim 12, wherein a height of the second access of the buffering chamber along the vertical axis is smaller than or equal to one third of a height of the buffering chamber along the vertical axis.

14. The electronic component testing equipment as claimed in claim 1, wherein a dry air flow is supplied by the dry air supplying device into the testing chamber and arranged adjacent to the second access.